

ABSTRACT

A method for analyzing waviness of a surface. The method includes measuring a height of the surface, producing a set of data points indicative of a waviness profile, selecting a subset of the set of data points, calculating a waviness height of the subset, repeating the selecting, determining, and calculating steps for additional subsets until all members of the set of data points have been selected, and selecting a maximum waviness height value from the waviness heights calculated for each subset. The height of the surface may be measured over a distance longer than the length over which waviness assessment is required.